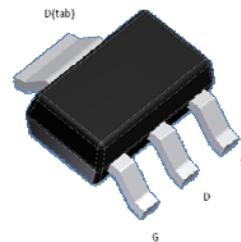
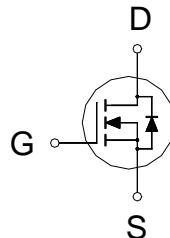


**N-Channel Logic Level Enhancement Mode Field Effect Transistor**

**Product Summary:**

BV <sub>DSS</sub>	200V
R <sub>DSON</sub> (MAX.)	0.5Ω
I <sub>D</sub>	1.6A



UIS, 100% Tested

Pb-Free Lead Plating & Halogen Free



**ABSOLUTE MAXIMUM RATINGS (T<sub>C</sub> = 25 °C Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNIT
Gate-Source Voltage	V <sub>GS</sub>	±30	V
Continuous Drain Current	I <sub>D</sub>	1.6	A
		1	
Pulsed Drain Current <sup>1</sup>	I <sub>DM</sub>	6.4	
Power Dissipation	P <sub>D</sub>	6.25	W
		2.5	
Operating Junction & Storage Temperature Range	T <sub>j</sub> , T <sub>stg</sub>	-55 to 150	°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Case	R <sub>θJC</sub>	20	150	°C / W
Junction-to-Ambient	R <sub>θJA</sub>			

<sup>1</sup>Pulse width limited by maximum junction temperature.

<sup>2</sup>Duty cycle ≤ 1%

**ELECTRICAL CHARACTERISTICS ( $T_c = 25^\circ\text{C}$ , Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	200			V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$	3.0	4.0	5.0	
Gate-Body Leakage	$I_{\text{GSS}}$	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 30\text{V}$			$\pm 100$	nA
Zero Gate Voltage Drain Current	$I_{\text{DSS}}$	$V_{\text{DS}} = 160\text{V}, V_{\text{GS}} = 0\text{V}$			1	$\mu\text{A}$
		$V_{\text{DS}} = 130\text{V}, V_{\text{GS}} = 0\text{V}, T_j = 125^\circ\text{C}$			25	
On-State Drain Current <sup>1</sup>	$I_{\text{D}(\text{ON})}$	$V_{\text{DS}} = 5\text{V}, V_{\text{GS}} = 10\text{V}$	1.6			A
Drain-Source On-State Resistance <sup>1</sup>	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = 10\text{V}, I_D = 0.8\text{A}$		0.4	0.5	$\Omega$
Forward Transconductance <sup>1</sup>	$g_{\text{fs}}$	$V_{\text{DS}} = 5\text{V}, I_D = 0.8\text{A}$		2		S
<b>DYNAMIC</b>						
Input Capacitance	$C_{\text{iss}}$	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 25\text{V}, f = 1\text{MHz}$		803		pF
Output Capacitance	$C_{\text{oss}}$			19		
Reverse Transfer Capacitance	$C_{\text{rss}}$			16		
Total Gate Charge <sup>1,2</sup>	$Q_g$	$V_{\text{DS}} = 100\text{V}, V_{\text{GS}} = 10\text{V}, I_D = 0.8\text{A}$		21.3		nC
Gate-Source Charge <sup>1,2</sup>	$Q_{\text{gs}}$			2.9		
Gate-Drain Charge <sup>1,2</sup>	$Q_{\text{gd}}$			6		
Turn-On Delay Time <sup>1,2</sup>	$t_{\text{d}(\text{on})}$	$V_{\text{DS}} = 100\text{V}, I_D = 0.5\text{A}, V_{\text{GS}} = 10\text{V}, R_{\text{GS}} = 6\Omega$		20		nS
Rise Time <sup>1,2</sup>	$t_r$			60		
Turn-Off Delay Time <sup>1,2</sup>	$t_{\text{d}(\text{off})}$			20		
Fall Time <sup>1,2</sup>	$t_f$			50		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (<math>T_c = 25^\circ\text{C}</math>)</b>						
Continuous Current	$I_s$				1.6	A
Pulsed Current <sup>3</sup>	$I_{\text{SM}}$				6.4	
Forward Voltage <sup>1</sup>	$V_{\text{SD}}$	$I_F = I_s, V_{\text{GS}} = 0\text{V}$			1.5	V

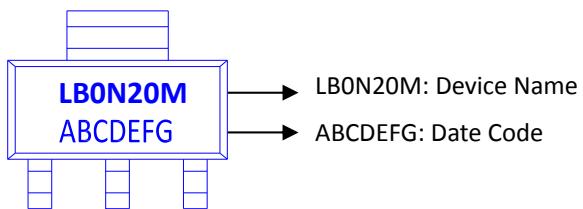
<sup>1</sup>Pulse test : Pulse Width  $\leq 300 \mu\text{sec}$ , Duty Cycle  $\leq 2\%$ .

<sup>2</sup>Independent of operating temperature.

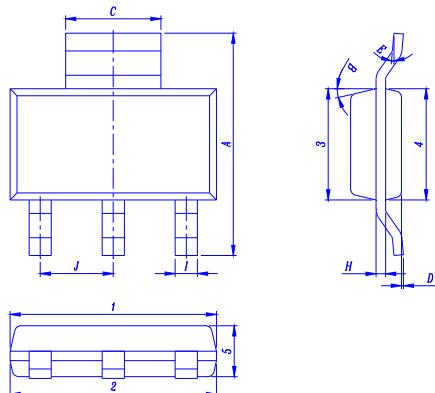
<sup>3</sup>Pulse width limited by maximum junction temperature.

### Ordering & Marking Information:

Device Name: LBON20M for SOT-223



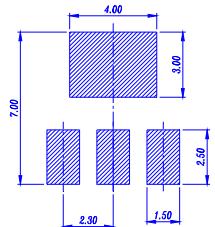
### Outline Drawing



Dimension in mm

Dimension	A	C	D	E	I	H	B	J	1	2	3	4	5
Min.	6.70	2.90	0.02	0°	0.60	0.25			6.30	63.0	3.30	3.30	1.40
Typ.								13°	2.30				
Max.	7.30	3.10	0.10	10°	0.80	0.35			6.70	6.70	3.70	3.70	1.80

### Recommended minimum pads



### TYPICAL CHARACTERISTICS

